Sear	ch N	lotes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/033,746	CHAN ET AL.
Examiner	Art Unit
Isaac M. Woo	2166

SEARCHED				
Class	Subclass	Date	Examiner	
707	100-104.1	5/17/2007	IW	
715	517-530	5/17/2007	IW	
	,			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	
PGPUB & USPAT - text search - see history printout(s)		5/17/2007	IW

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
See search history printout(s), ACM, IEEE, Google	5/17/07	IW
Consulted with Tod Swan, No 101 problem	1/11/2007	: IW
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